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U.S. PATENT DOCUMENTS											
		Grant Date	Name			Class		Sub Class	Filing Date		
an	AA 5,233,191 8/3/93 Nogu			chi et al.	- 4		50	306	4/2/91		
m	AB	5,459,404	10/17/95	Josephs			324		751	3/28/94	
pn	AC	5,994,914	11/30/99	Tsuruta			324		765	7/25/97	
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U.S. PATENT DOCUMENTS												
	Examiner Document Grant Initial* Number Date					Name arov			ass	Sub Class	Filing Dat	
	M	BA 5,957,749 09/28/99 Fi							1	6		
	Fin	BB 5,991,022 04/27/99 Buer			Buer	mann et al.			6	319		
		ВС										
		BD										
		BE										
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				Filing Date August 10	Group: 2877						
U.S. PATENT DOCUMENTS											
	Examiner Document Grant Initial* Number Date			Name			Class	Sub Class	Filing Date		
RM	AA	5,067,805	11/26/91	Corl	e et al.	359	235				
Pm	AB	5,486,701	01/23/96	Nort	on et al.		250	372			
RAK	AC	5,517,312	05/14/96	Fina	rov		356	386			
m	AD	5,608,526	03/04/97	Piwo	nka-Corle et	al.	356	369			
Ar	AE	5,682,242	10/28/97	Eylo	n		356	401			
A				on et al.		250	372				
m	AG	5,859,424	01/12/99	Nort	Norton et al.			226			
M	АН	5,885,045	03/23/99	Rush	Rush			417			
m	AI	5,889,593	03/30/99	Bareket			356	445			
M	АJ	5,943,122	08/24/99	Holm	Holmes			73			
			FOREIG	N PAT	ENT DOCUMENT	rs	- -				
Examiner Document Grant Initial* Number Date				Country Class		Sub Clas		Translation Yes No			
n	_AK	EP0973068		EPO				х			
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	OTHE	R ART (Inclu	ding Autho	r, Ti	tle, Date, I	ertine	nt Pag	es, Etc.	.)		
Nanometrics News Release, "Applied Materials/Nanometrics Sign Pact For Metrology Integration", Copyright 1998 Worldwide Videotex, Electro Manufacturing, Nov. 1998, No. 11, Vol. 11.											
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